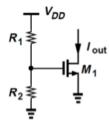
Chapter 5: Current Mirrors and Biasing Techniques

- 5.1 Basic Current Mirrors
- 5.2 Cascode Current Mirrors
- 5.3 Active Current Mirrors
- 5.4 Biasing Techniques

Basic Current Mirrors

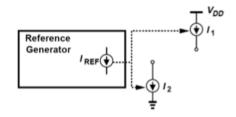


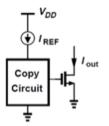
AssumingM1 is in saturation, we can write

$$I_{out} \approx \frac{1}{2} \mu_n C_{ox} \frac{W}{L} \left(\frac{R_2}{R_1 + R_2} V_{DD} - V_{TH} \right)^2. \label{eq:Iout}$$

- The threshold voltage may vary by 50 to 100 mV from wafer to wafer
- Both μn and VTH exhibit temperature dependence
- We must seek other methods of biasingMOS current sources.

Conceptual means of copying currents



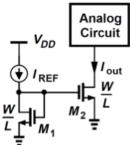


 Use of a reference to generate various currents.

$$I_{out} = f[f^{-1}(I_{REF})] = I_{REF}$$

 Two identical MOS devices that have equal gate-source voltages and operate in saturation carry equal currents

Effect of Channel-Length Modulation



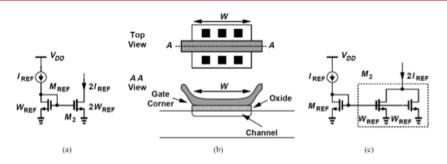
Neglecting channel-length modulation, we can write

$$\begin{split} I_{REF} & = & \frac{1}{2} \mu_n C_{ox} \left(\frac{W}{L} \right)_1 (V_{GS} - V_{TH})^2 \\ I_{out} & = & \frac{1}{2} \mu_n C_{ox} \left(\frac{W}{L} \right)_2 (V_{GS} - V_{TH})^2, \end{split}$$

$$I_{out} = \frac{(W/L)_2}{(W/L)_1} I_{REF}.$$

 $I_{out} = \frac{(W/L)_2}{(W/L)_1} I_{REF}.$ Allows precise copying of the current with no dependence on process and temperature

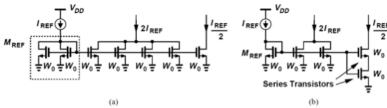
Sizing issues



- Current mirrors usually employ the same length for all of the transistors.
- Current ratioing is achieved by only scaling the width of transistors.
- Direct scaling of the width also faces difficulties.
- We thus prefer to employ a "unit" transistor and create copies by repeating such a device.

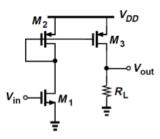
Sizing Issues

 How do we generate a current equal to IREF /2=2 from IREF?



- (a) half-width device, and (b) series transistors
- Approach (b) preserves an effective length of (Ldrawn-2LD) for each unit, yielding an equivalent length of 2(Ldrawn - 2LD)
- Current mirrors can process signals as well, example next slide.

Example

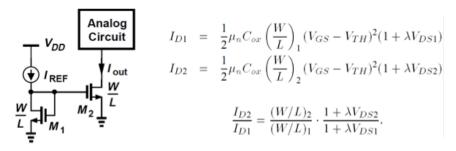


 Calculate the small-signal voltage gain of the circuit shown in Figure.

$$I_{D2} = I_{D1}$$
 $I_{D3} = I_{D2}(W/L)_3/(W/L)_2$

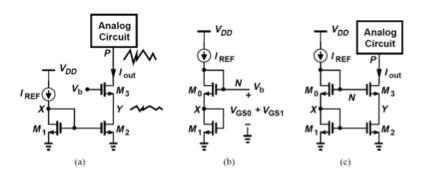
- Gain=
$$g_{m1}R_L(W/L)_3/(W/L)_2$$

Cascode Current Mirrors



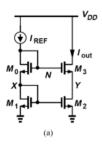
- While $V_{DS1}=V_{GS1}=V_{GS2}$, V_{DS2} may not equal V_{GS2}
- We can (a) force VDS2 to be equal to VDS1, or (b) force VDS1 to be equal to VDS2.

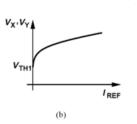
First Approach



- A cascode device can shield a current source, thereby reducing the voltage variations across it.
- But, how do we ensure that VDS2 = VDS1?
- We must generate V_b such that V_b V_{GS3} = V_{DS1}(= V_{GS1})

Example

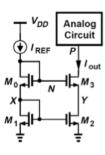




sketch VX and VY as a function of IREF. If IREF requires 0.5 V to operate as a current source, what is its maximum value?

$$\begin{split} V_Y &= V_X \approx \sqrt{2I_{REF}/[\mu_n C_{ox}(W/L)_1]} + V_{TH1} \\ V_N &= V_{GS0} + V_{GS1} \\ &= \sqrt{\frac{2I_{REF}}{\mu_n C_{ox}}} \left[\sqrt{\left(\frac{L}{W}\right)_0} + \sqrt{\left(\frac{L}{W}\right)_1} \right] + V_{TH0} + V_{TH1} \\ V_{DD} &- \sqrt{\frac{2I_{REF}}{\mu_n C_{ox}}} \left[\sqrt{\left(\frac{L}{W}\right)_0} + \sqrt{\left(\frac{L}{W}\right)_1} \right] - V_{TH0} - V_{TH1} = 0.5 \text{ V} \\ I_{REF,max} &= \frac{\mu_n C_{ox}}{2} \frac{(V_{DD} - 0.5 \text{ V} - V_{TH0} - V_{TH1})^2}{(\sqrt{(L/W)_0} + \sqrt{(L/W)_1})^2}. \end{split}$$

Example



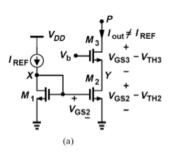
 the minimum allowable voltage at node P is equal to

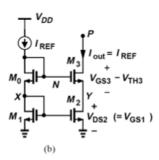
$$V_N - V_{TH} = V_{GS0} + V_{GS1} - V_{TH}$$

= $(V_{GS0} - V_{TH}) + (V_{GS1} - V_{TH}) + V_{TH}$

- The cascode mirror "wastes" one threshold voltage in the headroom.
- Because V_{DS2} = V_{GS2}, whereas V_{DS2} could be as low as V_{GS2}-V_{TH} while maintaining M2 in saturation.

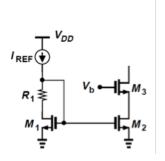
Approach summary





- In Fig(a), Vb is chosen to allow the lowest possible value of VP but the output current does not accurately track IREF.
- In Fig(b), a higher accuracy is achieved, but the minimum level at P is higher by one threshold voltage.

Second Approach

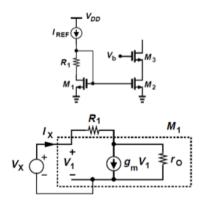


- Consider the branch shown in Fig. 5.16(b)
- As a candidate and write V_b = V_{GS5} + R₆I₆.

$$R_1 I_{REF} \approx V_{TH1}$$

$$V_b = V_{GS3} + (V_{GS1} - V_{TH1})$$

Small signal Model



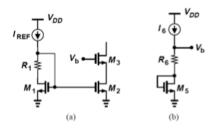
$$\frac{V_X-I_XR_1}{r_O}+g_mV_X=I_X.$$

$$\frac{V_X}{I_X}=\frac{R_1+r_O}{1+g_mr_O},$$

- Reduces to 1/gm in the absence of channellength modulation.
- Thus, from a small-signal point of view, the combination is close to a diode-connected device.
- But
 - (1) It may be difficult to guarantee that
 - guarantee that $R_1I_{REF} \approx V_{TH1}$ (2) The generation of

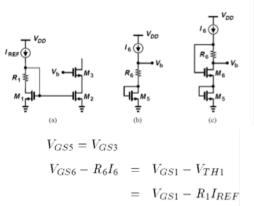
is not s
$$V_b = V_{GS3} + (V_{GS1} - V_{TH1})$$

Generate Vb



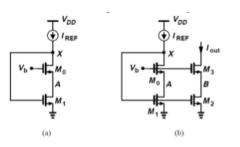
- Consider the branch shown in Fig(b) as a candidate and write Vb = VGS5 + R6I6.
- V_{GS5} = V_{GS3}
- However, the condition $R_{6I_6} = V_{GS1} V_{TH1} = V_{GS1} R_1I_{REF}$ is hard to meet.

Generate Vb



- It is now possible to ensure that VGS6 and VGS1 track each other.
- For example, we may simply choose I6 = IREF, R6 = R1, and (W/L)6 = (W=/L)1

Another circuit topology



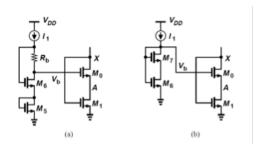
In this case

$$V_{DS1} = V_b - V_{GS0}$$

- Must have $V_b-V_{TH0}\leq V_X = V_{GS1}$ for M0 to be saturated and $V_{GS1}-V_{TH1}\leq V_A = V_b-V_{GS0}$ for M1 to be saturated.
- A solution exists it

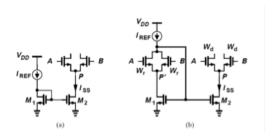
• We must therefore Sizewio to ensure its overurive is well below VTH1.

How to generate Vb



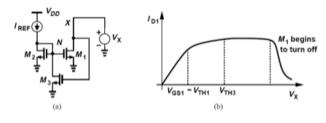
- In figure (a) $V_{DS6} = V_{GS6} R_b I_1 \approx V_{GS1} V_{TH1}$
- Some inaccuracy nevertheless arises because M5 does not suffer from body effect whereas M0 does.
- Also, the magnitude of R6*I1 is not well-controlled.
- A simpler alternative is shown in Fig(b)

Example



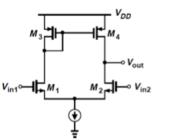
- Voltage headroom is too small to allow the use of a cascode current source. Devise a method to reduce the current mirror error due to channel-length modulation.
- The voltages at P0 and P track even if the CM level at A and B varies.
- The two differential pairs must incorporate the same lengths and scale their widths according to Wr/Wd = IREF/ISS.

Example



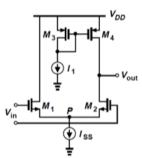
- An alternative current mirror exhibiting a high output impedance.
- Small signal: If we choose $g_{m3}g_{m1}/g_{m2}\approx r_{O1}^{-1}$ the net change in ID1 is small.
- · Figure b for large signal.
- The above circuit does pose its own voltage headroom limitation: Vx must exceed VTH3.

Active Current Mirrors



- A five-transistor "operational transconductance amplifier" (OTA).
- Note that the output is single-ended, hence the circuit is sometimes used to convert differential signals to a single-ended output.

Quick Calculation



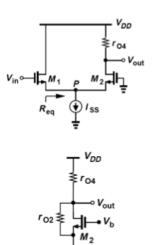
- We may simply discard one output of a differential pair as shown in Fig.
- What is the small-signal gain?

$$|A_v| = G_m R_{out}$$

$$|A_v| = \frac{g_{m1}}{2}[(2r_{O2})||r_{O4}].$$

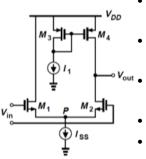
Second Approach

We calculate Vp /Vin and Vout/Vp

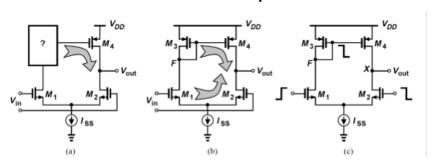


$$\begin{split} \frac{V_P}{V_{in}} &= \frac{R_{eq}||r_{O1}}{R_{eq}||r_{O1} + \frac{1}{g_{m1}}} \\ R_{eq} &= \frac{r_{O2} + r_{O4}}{1 + g_{m2}r_{O2}} \\ \\ \frac{V_P}{V_{in}} &= \frac{g_{m1}r_{O1}(r_{O2} + r_{O4})}{(1 + g_{m1}r_{O1})(r_{O2} + r_{O4}) + (1 + g_{m2}r_{O2})r_{O1}} \\ \\ \frac{V_{out}}{V_P} &= \frac{(1 + g_{m2}r_{O2})r_{O4}}{r_{O2} + r_{O4}}. \\ \\ \frac{V_{out}}{V_{in}} &= \frac{g_{m2}r_{O2}r_{O4}}{2r_{O2} + r_{O4}} \\ &= \frac{g_{m2}}{2}[(2r_{O2})||r_{O4}] \end{split}$$

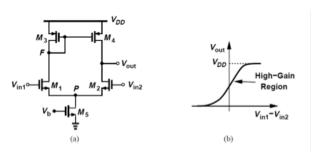
Differential Pair with Active Load



- The small-signal draincurrent of M1 is "wasted."
- It is desirable to utilize this current with proper polarity at the output.
- This can be accomplished by the five-transistor OTA.
- M3 enhances the gain.
- The five-transistor OTA is also called a differential pair with active load.

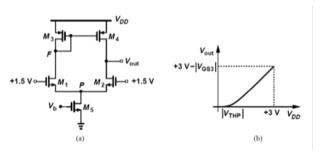


Large-Signal Analysis



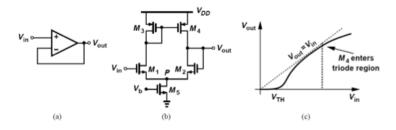
- If Vin1 is much more negative than Vin2, Vout = 0.
- As Vin1 approaches Vin2, The output voltage then depends on the difference between ID4 and ID2. For a small difference between Vin1 and Vin2, both M2 and M4 are saturated, providing a high gain.
- As Vin1 becomes more positive than Vin2, allowing Vout to rise and eventually driving M4 into the triode region.

Example



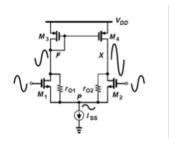
- For VDD = 3 V, symmetry requires that V_{out} = V_F.
- As VF and Vout fall below +1:5 V -V_{TH}, M1 and M2 enter the triode region, but their drain currents are constant if M5 is saturated.
- Eventually M5 into the triode region. Thereafter, the bias current of all of the transistors drops, lowering the rate at which V_{out} decreases.

Example



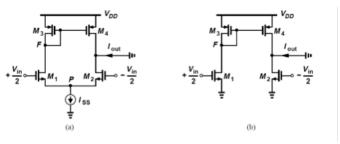
- Sketch the large-signal input-output characteristic of the unity-gain buffer shown in Fig if the op amp is realized as a five-transistor OTA.
- We begin with V_{in} = 0 and note that M1,M3, and M4 are off.
- As Vin rises, V_{out} ≈ Vin. This unity-gain action continues as Vin increases.
- For a sufficiently high Vin: M1 and M4 went to triode region.

Small-Signal Analysis



- With small differential inputs, the voltage swings at nodes F and X are vastly different.
- The effects of VF and Vx at node P (through ro1 and ro2, respectively) do not cancel each other and this node cannot be considered a virtual ground.

Approximate Analysis

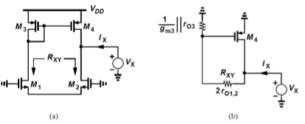


Node P can be approximated by a virtual ground.

$$I_{D1} = |I_{D3}| = |I_{D4}| = g_{m1,2}V_{in}/2$$

 $I_{D2} = -g_{m1,2}V_{in}/2$
 $I_{out} = -g_{m1,2}V_{in}$
 $|G_m| = g_{m1,2}$

Calculation of Rout



- Any current flowing intoM1 must flow out of M2, and the role of the two transistors can be represented by a resistor $R_{XY} = 2r_{O1.2}$
- The current drawn from Vx by Rxy is mirrored by M3 ontoM4 with unity gain.

$$I_X = \frac{V_X}{2r_{O1,2} + \frac{1}{g_{m3}}||r_{O3}} \left[1 + \left(\frac{1}{g_{m3}}||r_{O3} \right) g_{m4} \right] + \frac{V_X}{r_{O4}}$$

For
$$2r_{O1,2} \gg (1/g_{m3})||r_{O3}||$$

$$R_{out} \approx r_{O2} ||r_{O4}||$$

Exact Analysis

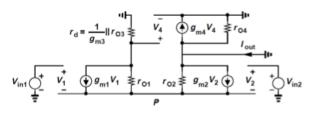
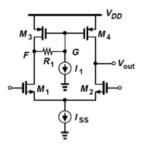


Figure 5.34. Equivalent circuit of five-transistor OTA

$$\begin{split} G_m R_{out} &= -g_{m1} r_{O1} r_{O4} \frac{2g_{m3} r_{O3} + 1}{(2g_{m3} r_{O3} + 1) r_{O4} + 2r_{O1}(1 + g_{m3} r_{O3}) + r_{O3}} \\ &= -\frac{g_{m1} r_{O1} r_{O4}}{r_{O1} + r_{O3}} \cdot \frac{2g_{m3} r_{O3} + 1}{2(g_{m3} r_{O3} + 1)}. \\ \\ |A_v| &= g_{m1}(r_{O1}||r_{O4}) \frac{2g_{m4} r_{O4} + 1}{2(g_{m4} r_{O4} + 1)} \end{split}.$$

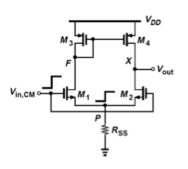
• We can viewthis result as our approximate solution, $g_{m1}(r_{O1}||r_{O4})$. multiplied by a "correction" factor that is less than unity.

Headroom Issues



- The five-transistor OTA does not easily lend itself to low-voltage operation.
- The value of I1 must be much less than Iss/2.
- Insert a resistor in series with the gate and draw a constant current from it.

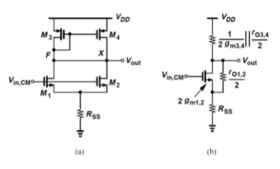
Common-Mode Properties



$$A_{CM} = \frac{\Delta V_{out}}{\Delta V_{in,CM}}.$$

$$\begin{array}{ll} A_{CM} & \approx & \displaystyle \frac{-\frac{1}{2g_{m3,4}} \bigg\| \frac{r_{O3,4}}{2}}{\frac{1}{2g_{m1,2}} + R_{SS}} \\ & = & \displaystyle \frac{-1}{1 + 2g_{m1,2}R_{SS}} \frac{g_{m1,2}}{g_{m3,4}} \end{array}$$

CMRR

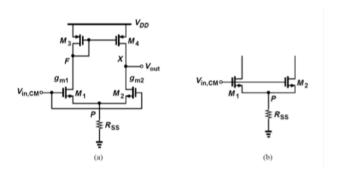


(a) Simplified circuit of Fig. 5.37, (b) equivalent circuit of (a).

$$\begin{split} CMRR &= \left|\frac{A_{DM}}{A_{CM}}\right| \\ &= g_{m1,2}(r_{O1,2}||r_{O3,4})\frac{g_{m3,4}(1+2g_{m1,2}R_{SS})}{g_{m1,2}} \\ &= (1+2g_{m1,2}R_{SS})g_{m3,4}(r_{O1,2}||r_{O3,4}). \end{split}$$

 Even with perfect symmetry, the output signal is corrupted by input CM variations.

Effect of Mismatches

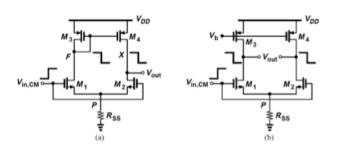


- we consider the case where the input transistors exhibit slightly different transconductances
- · How does Vout depend on Vincm?

$$\frac{\Delta V_{out}}{\Delta V_{in,CM}} \approx \frac{(g_{m1} - g_{m2})r_{O3} - g_{m2}/g_{m3}}{1 + (g_{m1} + g_{m2})R_{SS}}.$$

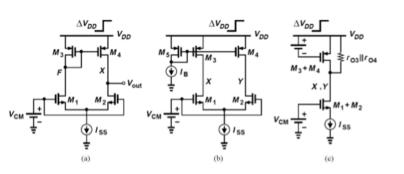
• This result contains the additional term $(g_{m1}-g_{m2})r_{O3}$

Other Properties



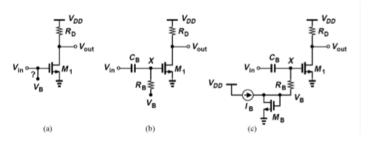
- A finite CMRR even with perfectly matched transistors.
- The supply rejection of this OTA is inferior.
- Change VDD by a small amount, how much does VF change?

Other Properties



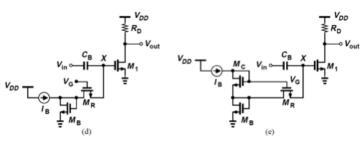
- For (a), The gain from VDD to Vout is about unity.
- · Now consider the fully-differential topology in Fig(b).
- In this case, too, the output voltages change by ∆VDD but their difference remains intact.
- · This circuit requires common-mode feedback.

Biasing Techniques



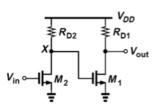
- Simple CS Stage
- How do we ensure that VB does not "fight" Vin?
- Couple V_{in} capacitively and establish a high impedance for V_B.
- Node X in Fig (b) must have a dc path to a voltage.
- The bias voltage must be generated by a diodeconnected device
- Typically select IB about one-tenth to one-fifth of ID1 so as to minimize the power.

Biasing Using a MOSFET



- The capacitor and the resistor may occupy a large chip area.
- The capacitor introduces its own parasitics.
- In applications requiring a large RC product, one can replace RB with a long, narrow MOSFET.
- But how do we guarantee that MR does not turn off?
- The overdrive of MR must be well controlled. This difference can be created by means of a diodeconnected device.

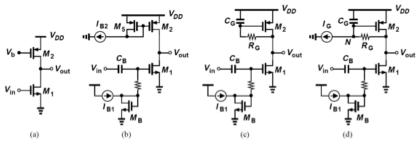
Direct Coupling



Direct coupling between two stages.

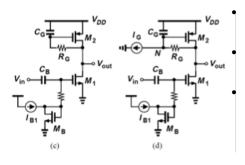
- Possible to remove the input coupling capacitor and provide the bias voltage from the preceding stage?
- The bias conditions of M1 are influenced by those of M2.
- The PVT variations are amplified.
- One can employ direct coupling between two stages if each has a low gain.

CS Stage with Current-Source Load

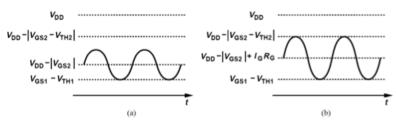


- If the copied currents in Fig (b) are not exactly equal, each transistor wants to impose its own current.
- To resolve this issue, we modify the circuit as shown in Fig (c).
- Select $A_v = -g_{m1}(r_{O1}||r_{O2}||R_G)$

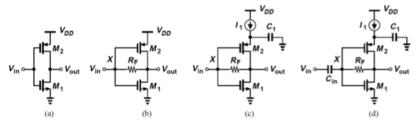
Example



Compare the maximum allowable voltage swings. In Fig (c), the up-swing cannot reach its maximum. In Fig. 5.45(d), on the other hand, IGRG can shift the operating point such that the down-swing and the up-swing are approximately equal.

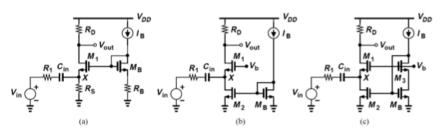


Complementary CS Stage



- Shown in Fig. (b), each transistor is configured as a diode-connect device and guaranteed to operate in saturation.
- · Self-biased topology.
- To define the bias current accurately, we modify the circuit as shown in Fig. (c).
- Since the bias voltage at node X must track Vout, the input must be capacitively coupled.

CG Biasing

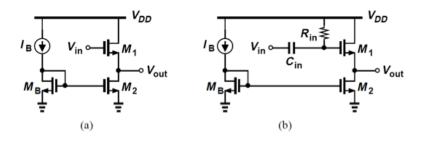


 The circuit of Fig. (a) faces difficulties in low-voltage design.

$$\frac{V_X}{V_{in}} = \frac{\frac{1}{g_{m1} + g_{mb1}} || R_S}{\frac{1}{g_{m1} + g_{mb1}} || R_S + R_1}$$

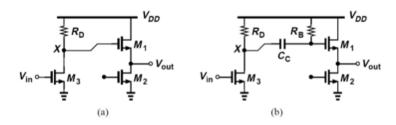
- RS may reach or even exceed RD.
- · Replace RS with a current source.

Source Follower Biasing



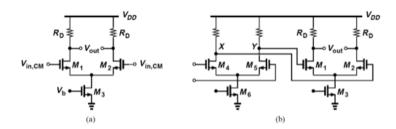
- In applications where the input dc voltage may vary considerably, capacitive coupling can be used.
- Study the performance with and without capacitive coupling between the two stages.

Use of SF



- In Fig (a), the minimum drain voltage of M3 is given by V_{GS1} + V_{DS2min}, leaving little for the allowable voltage drop across R_D.
- Fig (b), on the other hand, the first stage's gain can be independently maximized.

Differential Pair Biasing



- Since the bias currents of M1 and M2 in Fig. (a) are relatively insensitive to their gate voltages, we can directly connect their gates to the preceding stage.
- If the bias value of VX and VY is chosen equal to two overdrives above ground, then it is an excessively low common-mode level for the second stage.
- May resort to capacitive coupling in some cases.